74LV00 Quad 2-input NAND gate Rev. 03 — 20 December 2007

Product data sheet

General description 1.

The 74LV00 is a low-voltage Si-gate CMOS device that is pin and function compatible with 74HC00 and 74HCT00.

The 74LV00 provides a quad 2-input NAND function.

2. **Features**

- Wide operating voltage: 1.0 V to 5.5 V
- Optimized for low voltage applications: 1.0 V to 3.6 V
- Accepts TTL input levels between V_{CC} = 2.7 V and V_{CC} = 3.6 V
- Typical output ground bounce < 0.8 V at V_{CC} = 3.3 V and T_{amb} = 25 °C
- Typical HIGH-level output voltage (V_{OH}) undershoot: > 2 V at V_{CC} = 3.3 V and $T_{amb} = 25 \, ^{\circ}C$
- ESD protection:
 - ◆ HBM JESD22-A114E exceeds 2000 V
 - MM JESD22-A115-A exceeds 200 V
- Multiple package options
- Specified from -40 °C to +85 °C and from -40 °C to +125 °C

Ordering information

Table 1. **Ordering information**

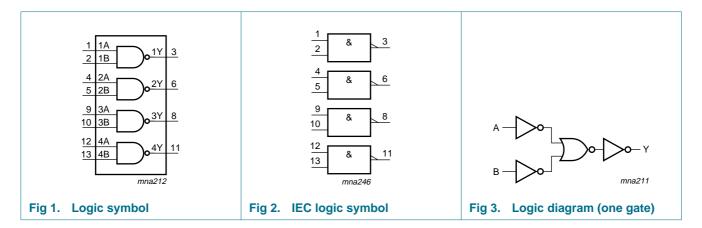
Type number	Package			
	Temperature range	Name	Description	Version
74LV00N	-40 °C to +125 °C	DIP14	plastic dual in-line package; 14 leads (300 mil)	SOT27-1
74LV00D	–40 °C to +125 °C	SO14	plastic small outline package; 14 leads; body width 3.9 mm	SOT108-1
74LV00DB	–40 °C to +125 °C	SSOP14	plastic shrink small outline package; 14 leads; body width 5.3 mm	SOT337-1
74LV00PW	–40 °C to +125 °C	TSSOP14	plastic thin shrink small outline package; 14 leads; body width 4.4 mm	SOT402-1
74LV00BQ	–40 °C to +125 °C	DHVQFN14	plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 14 terminals; body $2.5\times3\times0.85$ mm	SOT762-1



Quad 2-input NAND gate

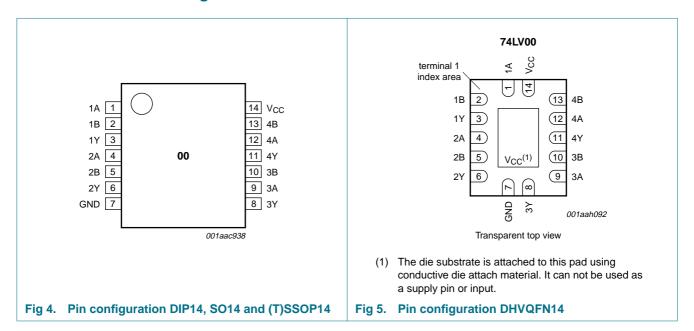
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4. Functional diagram



5. Pinning information

5.1 Pinning



5.2 Pin description

Table 2. Pin description

Symbol	Pin	Description
1A	1	data input
1B	2	data input
1Y	3	data output
2A	4	data input
2B	5	data input
2Y	6	data output

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Table 2. Pin description ... continued

Symbol	Pin	Description
GND	7	ground (0 V)
3Y	8	data output
3A	9	data input
3B	10	data input
4Y	11	data output
4A	12	data input
4B	13	data input
V _{CC}	14	supply voltage

6. Functional description

Table 3. Function table[1]

Input	Output	
nA	nB	nY
L	X	Н
X	L	Н
Н	Н	L

^[1] H = HIGH voltage level; L = LOW voltage level; X = don't care

7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	supply voltage		-0.5	+7.0	V
I _{IK}	input clamping current	$V_I < -0.5 \text{ V or } V_I > V_{CC} + 0.5 \text{ V}$	<u>[1]</u> _	±20	mA
l _{OK}	output clamping current	$V_O < -0.5 \text{ V or } V_O > V_{CC} + 0.5 \text{ V}$	<u>[1]</u> _	±50	mA
Io	output current	$V_{O} = -0.5 \text{ V to } (V_{CC} + 0.5 \text{ V})$	-	±25	mA
I _{CC}	supply current		-	50	mA
I _{GND}	ground current		-50	-	mA
T _{stg}	storage temperature		-65	+150	°C
P _{tot}	total power dissipation	$T_{amb} = -40 ^{\circ}\text{C} \text{ to } +125 ^{\circ}\text{C}$			
		DIP14 package	[2] _	750	mW
		SO14 package	[3] _	500	mW
		(T)SSOP14 package	<u>[4]</u> _	500	mW
		DHVQFN14 package	<u>[5]</u> _	500	mW

^[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

^[2] Ptot derates linearly with 12 mW/K above 70 °C.

^[3] P_{tot} derates linearly with 8 mW/K above 70 °C.

^[4] P_{tot} derates linearly with 5.5 mW/K above 60 °C.

^[5] P_{tot} derates linearly with 4.5 mW/K above 60 °C.

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8. Recommended operating conditions

Table 5. Recommended operating conditions

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{CC}	supply voltage		<u>[1]</u> 1.0	3.3	5.5	V
V_{I}	input voltage		0	-	V_{CC}	V
Vo	output voltage		0	-	V_{CC}	V
T _{amb}	ambient temperature		-40	+25	+125	°C
$\Delta t/\Delta V$	input transition rise and fall rate	$V_{CC} = 1.0 \text{ V to } 2.0 \text{ V}$	-	-	500	ns/V
		$V_{CC} = 2.0 \text{ V to } 2.7 \text{ V}$	-	-	200	ns/V
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	-	-	100	ns/V
		$V_{CC} = 3.6 \text{ V to } 5.5 \text{ V}$	-	-	50	ns/V

^[1] The static characteristics are guaranteed from V_{CC} = 1.2 V to V_{CC} = 5.5 V, but LV devices are guaranteed to function down to V_{CC} = 1.0 V (with input levels GND or V_{CC}).

9. Static characteristics

Table 6. Static characteristics

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	-40	°C to +8	35 °C	-40 °C to	+125 °C	Unit
			Min	Typ[1]	Max	Min	Max	1
V_{IH}	HIGH-level input voltage	V _{CC} = 1.2 V	0.9	-	-	0.9	-	V
		V _{CC} = 2.0 V	1.4	-	-	1.4	-	V
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2.0	-	-	2.0	-	V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	$0.7V_{CC}$	-	-	$0.7V_{CC}$	-	V
V_{IL}	LOW-level input voltage	$V_{CC} = 1.2 \text{ V}$	-	-	0.3	-	0.3	V
		$V_{CC} = 2.0 \text{ V}$	-	-	0.6	-	0.6	V
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	-	-	0.8	-	8.0	V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	-	-	$0.3V_{CC}$	-	$0.3V_{CC}$	V
V_{OH}	HIGH-level output voltage	$V_I = V_{IH}$ or V_{IL}						
		$I_O = -100 \ \mu A; \ V_{CC} = 1.2 \ V$	-	1.2	-	-	-	V
		I_O = $-100~\mu A$; V_{CC} = $2.0~V$	1.8	2.0	-	1.8	-	V
		I_O = $-100~\mu A$; V_{CC} = $2.7~V$	2.5	2.7	-	2.5	-	V
		I_O = $-100~\mu A$; V_{CC} = $3.0~V$	2.8	3.0	-	2.8	-	V
		$I_O = -100 \ \mu A; \ V_{CC} = 4.5 \ V$	4.3	4.5	-	4.3	-	V
		$I_{O} = -6 \text{ mA}; V_{CC} = 3.0 \text{ V}$	2.4	2.82	-	2.2	-	V
		$I_{O} = -12 \text{ mA}; V_{CC} = 4.5 \text{ V}$	3.6	4.2	-	3.5	-	V

Quad 2-input NAND gate

Table 6. Static characteristics ...continued Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	-40	°C to +8	5 °C	–40 °C to	+125 °C	Unit
			Min	Typ[1]	Max	Min	Max	
V_{OL}	LOW-level output voltage	$V_I = V_{IH}$ or V_{IL}						
		$I_O = 100 \mu A; V_{CC} = 1.2 V$	-	0	-	-	-	V
		$I_O = 100 \mu A; V_{CC} = 2.0 V$	-	0	0.2	-	0.2	V
		$I_O = 100 \mu A; V_{CC} = 2.7 V$	-	0	0.2	-	0.2	V
		$I_O = 100 \mu A; V_{CC} = 3.0 V$	-	0	0.2	-	0.2	V
		$I_O = 100 \mu A; V_{CC} = 4.5 V$	-	0	0.2	-	0.2	V
		$I_O = 6 \text{ mA}; V_{CC} = 3.0 \text{ V}$	-	0.25	0.40	-	0.50	V
		$I_O = 12 \text{ mA}; V_{CC} = 4.5 \text{ V}$	-	0.35	0.55	-	0.65	V
I _I	input leakage current	$V_I = V_{CC}$ or GND; $V_{CC} = 5.5 \text{ V}$	-	-	1.0	-	1.0	μΑ
I _{CC}	supply current	$V_1 = V_{CC}$ or GND; $I_O = 0$ A; $V_{CC} = 5.5 \text{ V}$	-	-	20.0	-	40	μΑ
ΔI_{CC}	additional supply current	per input; $V_I = V_{CC} - 0.6 \text{ V}$; $V_{CC} = 2.7 \text{ V}$ to 3.6 V	-	-	500	-	850	μΑ
CI	input capacitance		-	3.5	-	-	-	pF

^[1] Typical values are measured at T_{amb} = 25 °C.

10. Dynamic characteristics

Table 7. Dynamic characteristics *GND = 0 V; For test circuit see Figure 7.*

Symbol	Parameter	Conditions		-40	°C to +85	S°C	–40 °C t	o +125 °C	Unit
				Min	Typ[1]	Max	Min	Max	
t _{pd}	propagation delay	nA, nB to nY; see Figure 6	[2]						
		V _{CC} = 1.2 V		-	45	-	-	-	ns
		V _{CC} = 2.0 V		-	15	26	-	31	ns
		V _{CC} = 2.7 V		-	11	18	-	23	ns
		$V_{CC} = 3.0 \text{ V to } 3.6 \text{ V; } C_L = 15 \text{ pF}$	[3]	-	7	-	-	-	ns
		V _{CC} = 3.0 V to 3.6 V	[3]	-	9.0	15	-	18	ns
		V _{CC} = 4.5 V to 5.5 V	[3]	-	6.5	11	-	14	ns
C _{PD}	power dissipation capacitance	$C_L = 50 \text{ pF}; f_i = 1 \text{ MHz};$ $V_I = \text{GND to } V_{CC}$	<u>[4]</u>	-	22	-	-	-	pF

^[1] All typical values are measured at T_{amb} = 25 °C.

 $P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma (C_L \times V_{CC}^2 \times f_o) \text{ where:}$

 f_i = input frequency in MHz, f_o = output frequency in MHz

C_L = output load capacitance in pF

V_{CC} = supply voltage in V

N = number of inputs switching

 $\Sigma(C_L \times V_{CC}{}^2 \times f_o)$ = sum of the outputs.

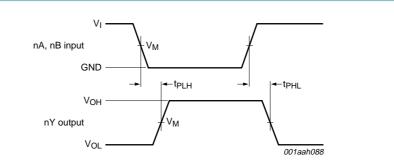
^[2] t_{pd} is the same as t_{PLH} and t_{PHL} .

^[3] Typical values are measured at nominal supply voltage (V_{CC} = 3.3 V and V_{CC} = 5.0 V).

^[4] C_{PD} is used to determine the dynamic power dissipation (P_D in μW).

Quad 2-input NAND gate

11. Waveforms



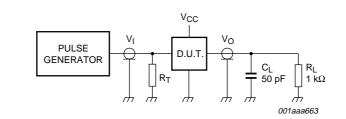
Measurement points are given in Table 8.

 $V_{\mbox{\scriptsize OL}}$ and $V_{\mbox{\scriptsize OH}}$ are typical voltage output levels that occur with the output load.

Fig 6. The input (nA, nB) to output (nY) propagation delays

Table 8. Measurement points

Supply voltage	Input	Output
V _{CC}	V _M	V _M
< 2.7 V	0.5V _{CC}	0.5V _{CC}
2.7 V to 3.6 V	1.5 V	1.5 V
≥ 4.5 V	0.5V _{CC}	0.5V _{CC}



Test data is given in Table 9.

Definitions test circuit:

 R_T = Termination resistance should be equal to output impedance Z_0 of the pulse generator.

R_L = Load resistance.

C_L = Load capacitance including jig and probe capacitance.

Fig 7. Load circuit for switching times

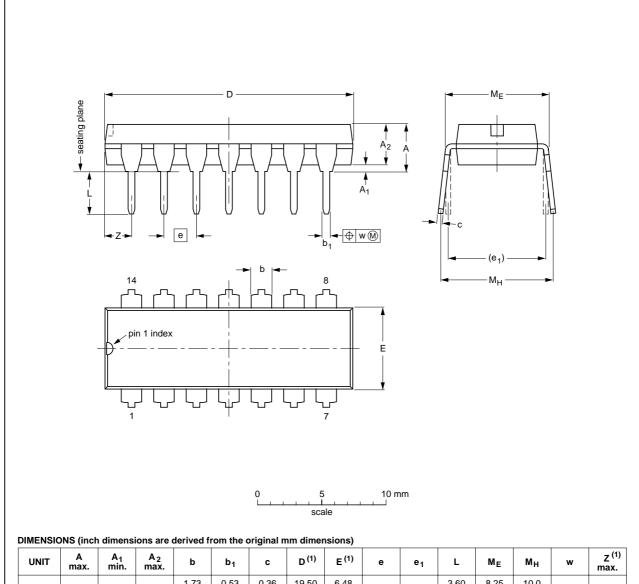
Table 9. Test data

Supply voltage	Input	
V _{CC}	V _I	t _r , t _f
< 2.7 V	V _{CC}	≤ 2.5 ns
2.7 V to 3.6 V	2.7 V	≤ 2.5 ns
≥ 4.5 V	V _{CC}	≤ 2.5 ns

12. Package outline

DIP14: plastic dual in-line package; 14 leads (300 mil)

SOT27-1



UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	С	D ⁽¹⁾	E (1)	е	e ₁	L	ME	Мн	w	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.13	0.53 0.38	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.2
inches	0.17	0.02	0.13	0.068 0.044	0.021 0.015	0.014 0.009	0.77 0.73	0.26 0.24	0.1	0.3	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.087

Note

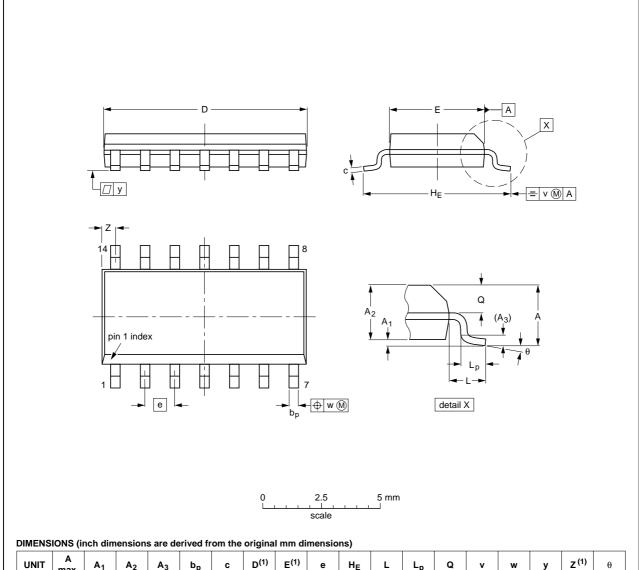
1. Plastic or metal protrusions of 0.25 mm (0.01 inch) maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	JEITA		PROJECTION	1330E DATE	
SOT27-1	050G04	MO-001	SC-501-14			99-12-27 03-02-13	
	VERSION	VERSION IEC	VERSION IEC JEDEC	VERSION IEC JEDEC JEITA	VERSION IEC JEDEC JEITA	VERSION IEC JEDEC JEITA PROJECTION	

Fig 8. Package outline SOT27-1 (DIP14)

SO14: plastic small outline package; 14 leads; body width 3.9 mm

SOT108-1



UNIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽¹⁾	е	HE	L	Lp	Q	v	w	у	z ⁽¹⁾	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	8.75 8.55	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8°
inches	0.069	0.010 0.004	0.057 0.049	0.01		0.0100 0.0075	0.35 0.34	0.16 0.15	0.05	0.244 0.228	0.041	0.039 0.016	0.028 0.024	0.01	0.01	0.004	0.028 0.012	0°

Note

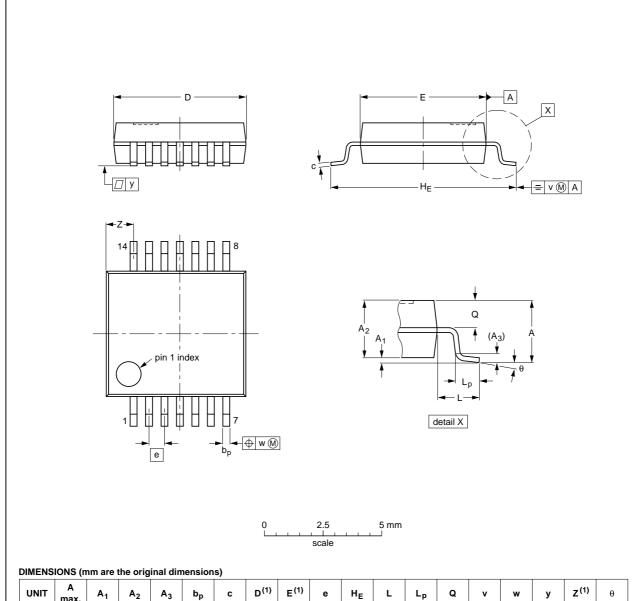
1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

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VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE	
SOT108-1	076E06	MS-012				99-12-27 03-02-19

Fig 9. Package outline SOT108-1 (SO14)

SSOP14: plastic shrink small outline package; 14 leads; body width 5.3 mm

SOT337-1



UNIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽¹⁾	е	HE	٦	Lp	Q	v	w	у	z ⁽¹⁾	θ
mm	2	0.21 0.05	1.80 1.65	0.25	0.38 0.25	0.20 0.09	6.4 6.0	5.4 5.2	0.65	7.9 7.6	1.25	1.03 0.63	0.9 0.7	0.2	0.13	0.1	1.4 0.9	8° 0°

Note

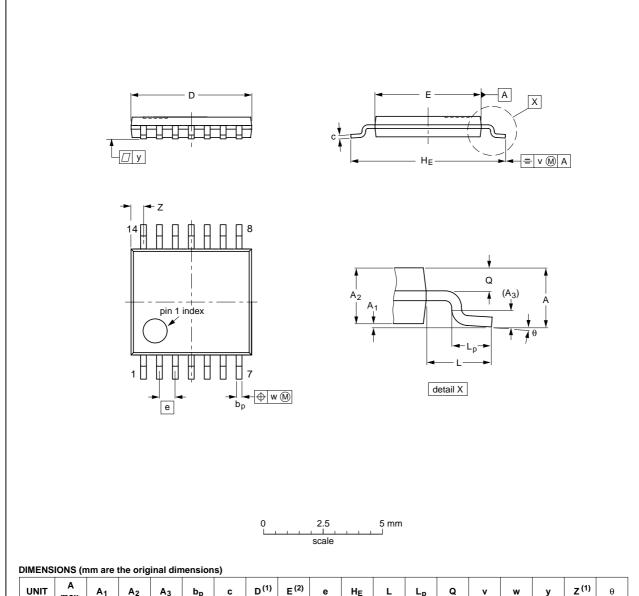
1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

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VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT337-1		MO-150			-99-12-27 03-02-19

Fig 10. Package outline SOT337-1 (SSOP14)

TSSOP14: plastic thin shrink small outline package; 14 leads; body width 4.4 mm

SOT402-1



UNIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽²⁾	е	HE	L	Lp	ø	v	w	у	Z ⁽¹⁾	θ
mm	1.1	0.15 0.05	0.95 0.80	0.25	0.30 0.19	0.2 0.1	5.1 4.9	4.5 4.3	0.65	6.6 6.2	1	0.75 0.50	0.4 0.3	0.2	0.13	0.1	0.72 0.38	8° 0°

Notes

- 1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- 2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	ENCES		EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE	
SOT402-1		MO-153				99-12-27 03-02-18

Fig 11. Package outline SOT402-1 (TSSOP14)

DHVQFN14: plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 14 terminals; body 2.5 x 3 x 0.85 mm SOT762-1

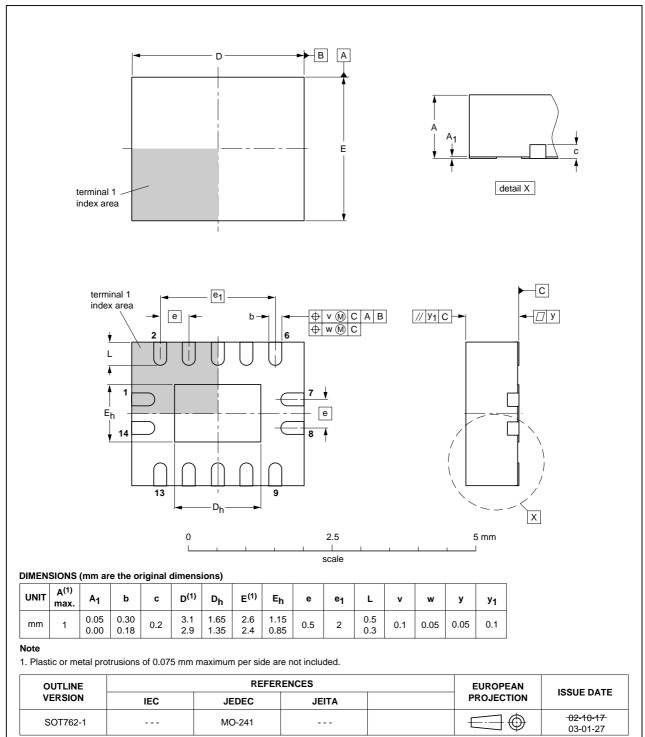


Fig 12. Package outline SOT762-1 (DHVQFN14)

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74LV00 **NXP Semiconductors**

Quad 2-input NAND gate

13. Abbreviations

Table 10. Abbreviations

Acronym	Description
CMOS	Complementary Metal Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
HBM	Human Body Model
MM	Machine Model
TTL	Transistor-Transistor Logic

14. Revision history

Table 11. Revision history

	•			
Document ID	Release date	Data sheet status	Change notice	Supersedes
74LV00_3	20071220	Product data sheet	-	74LV00_2
Modifications:	 The format of of NXP Semic 		designed to comply with	the new identity guidelines
	 Legal texts ha 	ve been adapted to the new	company name where	appropriate.
	 Section 3: DH 	VQFN14 package added.		
	 Section 7: der 	ating values added for DHV	QFN14 package.	
	• Section 12: ou	utline drawing added for DH	/QFN14 package.	
74LV00_2	19980420	Product specification	-	74LV00_1
74LV00_1	19970203	Product specification	-	-

Quad 2-input NAND gate

15. Legal information

15.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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NL17SG32P5T5G NL17SG86DFT2G NLU1G32CMUTCG NLV14001UBDR2G NLVVHC1G132DTT1G NLVVHC1G86DTT1G
NLX1G11AMUTCG NLX1G97MUTCG 746427X 74AUP1G17FW5-7 74LS38 74LVC1G08Z-7 74LVC32ADTR2G 74LVC1G125FW4-7
74LVC08ADTR2G MC74HCT20ADTR2G NLU1G08CMX1TCG NLV14093BDTR2G NLV17SZ00DFT2G NLV17SZ02DFT2G
NLV17SZ126DFT2G NLV27WZ17DFT2G NLV74HC02ADR2G NLV74HC08ADR2G NLVVHC1GT32DFT1G 74HC32S14-13 74LS133
74LVC1G32Z-7 M38510/30402BDA 74LVC1G86Z-7 74LVC2G08RA3-7 M38510/06202BFA NLV74HC08ADTR2G
NLV74HC14ADR2G